

800 MHz, 50 mW **Current Feedback Amplifier**

AD8001

FEATURES

Excellent Video Specifications (R_L = 150 Ω , G = +2) Gain Flatness 0.1 dB to 100 MHz 0.01% Differential Gain Error 0.025° Differential Phase Error Low Power

5.5 mA max Power Supply Current (55 mW)

High Speed and Fast Settling

880 MHz, -3 dB Bandwidth (G = +1)

440 MHz, -3 dB Bandwidth (G = +2)

1200 V/µs Slew Rate

10 ns Settling Time to 0.1%

Low Distortion

-65 dBc THD, $f_c = 5$ MHz

33 dBm 3rd Order Intercept, $F_1 = 10 \text{ MHz}$

-66 dB SFDR, f = 5 MHz

High Output Drive

70 mA Output Current

Drives Up to 4 Back-Terminated Loads (75 Ω Each) While Maintaining Good Differential Gain/Phase Performance (0.05%/ 0.25°)

APPLICATIONS

A-to-D Driver **Video Line Driver Professional Cameras** Video Switchers Special Effects **RF Receivers**

PRODUCT DESCRIPTION

The AD 8001 is a low power, high speed amplifier designed to operate on ±5 V supplies. The AD 8001 features unique

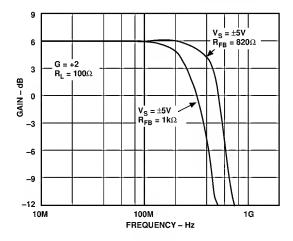
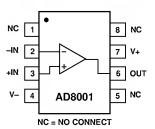


Figure 1. Frequency Response of AD8001

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FUNCTIONAL BLOCK DIAGRAM 8-Pin Plastic Mini-DIP and SOIC



transimpedance linearization circuitry. This allows it to drive video loads with excellent differential gain and phase performance on only 50 mW of power. The AD 8001 is a current feedback amplifier and features gain flatness of 0.1 dB to 100 M H z while offering differential gain and phase error of 0.01% and 0.025°. This makes the AD 8001 ideal for professional video electronics such as cameras and video switchers. Additionally, the AD 8001's low distortion and fast settling make it ideal for buffer high speed A-to-D converters.

The AD 8001 offers low power of 5.5 mA max ($V_S = \pm 5 \text{ V}$) and can run on a single +12 V power supply, while being capable of delivering up to 70 mA of load current. All this is offered in a small 8-pin DIP or 8-pin SOIC package. These features make this amplifier ideal for portable and battery powered applications where size and power is critical.

The outstanding bandwidth of 800 MHz along with 1200 V/µs of slew rate make the AD 8001 useful in many general purpose high speed applications where dual power supplies of up to ± 6 V and single supplies from 6 V to 12 V are needed. The AD 8001 is available in the industrial temperature range of -40°C to +85°C.

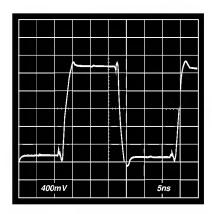


Figure 2. Transient Response of AD8001; 2 V Step, G = +2

One Technology Way, P.O. Box 9106, Norwood. MA 02062-9106, U.S.A. Tel: 617/329-4700 Fax: 617/326-8703

AD8001- SPECIFICATIONS (@ T_A = + 25°C, V_S = ± 5 V, R_L = 100 Ω , unless otherwise noted)

Model			AD8001	Α		
	Conditions	Min	Тур Мах		Units	
DYNAMIC PERFORMANCE -3 dB Small Signal Bandwidth, N Package R Package	$G=+2$, < 0.1 dB Peaking, $R_F=750~\Omega$ $G=+1$, < 1 dB Peaking, $R_F=1~k\Omega$ $G=+2$, < 0.1 dB Peaking, $R_F=681~\Omega$ $G=+1$, < 0.1 dB Peaking, $R_F=845~\Omega$	350 650 350	440 880 440		M H z M H z M H z M H z	
Bandwidth for 0.1 dB Flatness N Package R Package	-	85 100	715 110 125		M H Z M H Z M H Z	
Slew Rate	$G = +2, V_0 = 2 \text{ V Step}$ $G = -1, V_0 = 2 \text{ V Step}$	800 960	1000 1200		V/μs V/μs	
Settling Time to 0.1% Rise & Fall Time	$G = -1$, $V_0 = 2$ V Step $G = -1$, $V_0 = 2$ V Step, $R_F = 649$ Ω		10 1.4		ns ns	
NOISE/HARMONIC PERFORMANCE Total Harmonic Distortion	$f_{C} = 5 \text{ M H z}, V_{O} = 2 \text{ V p-p}$ $G = +2, R_{L} = 100 \Omega$		-65		dBc	
Input Voltage Noise Input Current Noise	f = 10 kHz f = 10 kHz, +In -In		2.0 2.0 18		n V/√Hz pA/√Hz pA/√Hz	
Differential Gain Error Differential Phase Error Third Order Intercept 1 dB Gain Compression SFDR	NTSC, $G = +2$, $R_L = 150 \Omega$ NTSC, $G = +2$, $R_L = 150 \Omega$ f = 10 M Hz f = 10 M Hz f = 5 M Hz		0.01 0.025 33 14 -66	0.025 0.04	% Degree dBm dBm dB	
DC PERFORM AN CE	1 – 3 14112		-00		QD	
Input Offset Voltage Offset Drift	T _{MIN} -T _{MAX}		2.0 2.0 10	5.5 9.0	mV mV μV/°C	
-Input Bias Current +Input Bias Current	T _{MIN} -T _{MAX}		5.0 3.0	25 35 6.0 10	±μΑ ±μΑ ±μΑ	
Open Loop Transresistance	$T_{MIN}-T_{MAX}$ $V_{O} = \pm 2.5 V$ $T_{MIN}-T_{MAX}$	250 175	900	10	±μΑ kΩ kΩ	
INPUT CHARACTERISTICS Input Resistance	+Input -Input		10 50		M Ω Ω	
Input Capacitance Input Common-M ode Voltage Range Common-M ode Rejection Ratio	+Input	F.0	1.5 3.2		pF ±V	
Offset Voltage -Input Current +Input Current	$V_{CM} = \pm 2.5 V$ $V_{CM} = \pm 2.5 V$, $T_{MIN} - T_{MAX}$ $V_{CM} = \pm 2.5 V$, $T_{MIN} - T_{MAX}$	50	54 0.3 0.2	1.0 0.7	dB μΑ/V μΑ/V	
OUTPUT CHARACTERISTICS Output Voltage Swing Output Current Short Circuit Current	$R_L = 150 \Omega$ $R_L = 37.5 \Omega$	2.7 50 85	3.1 70 110		±V mA mA	
POWER SUPPLY Operating Range Quiescent Current Power Supply Rejection Ratio	$T_{MIN}-T_{MAX}$ + V_{S} = +4 V to +6V, - V_{S} = -5 V - V_{S} = -4 V to -6 V, + V_{S} = +5 V	±3.0 60 50	5.0 75 56	±6.0 5.5	V mA dB dB	
-Input Current +Input Current	T MIN-T MAX T MIN-T MAX	30	0.5 0.1	2.5 0.5	μΑ/V μΑ/V	

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Specifications subject to change without notice.

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ABSOLUTE MAXIMUM RATINGS¹

Supply Voltage	٧
Internal Power Dissipation ²	
Plastic Package (N)	ts
Small Outline Package (R)	ts
Input Voltage (Common Mode) $\dots \pm V$	/s
Differential Input Voltage±1.2	٧
Output Short Circuit Duration	
O bserve Power D erating C urve	es
Storage T emperature Range N, R65°C to +125°	C
Operating Temperature Range (A Grade)40°C to +85°C	C
Lead Temperature Range (Soldering 10 sec) +300°	C

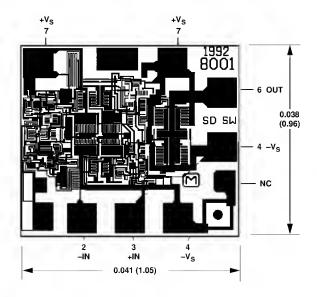
NOTES

¹Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

²Specification is for device in free air: 8-Pin Plastic Package: $\theta_{JA} = 90^{\circ}\text{C/W}$ att 8-Pin SOIC Package: $\theta_{JA} = 140^{\circ}\text{C/W}$ att

METALLIZATION PHOTO

Dimensions shown in inches and (mm). Connect Substrate to -V_s.



MAXIMUM POWER DISSIPATION

The maximum power that can be safely dissipated by the AD 8001 is limited by the associated rise in junction temperature. The maximum safe junction temperature for plastic encapsulated devices is determined by the glass transition temperature of the plastic, approximately +150°C. Exceeding this limit temporarily may cause a shift in parametric performance due to a change in the stresses exerted on the die by the package. Exceeding a junction temperature of +175°C for an extended period can result in device failure.

While the AD 8001 is internally short circuit protected, this may not be sufficient to guarantee that the maximum junction temperature (+150°C) is not exceeded under all conditions. To ensure proper operation, it is necessary to observe the maximum power derating curves.

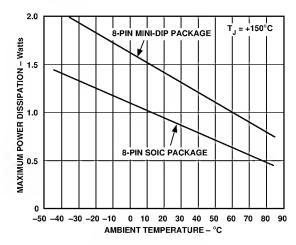


Figure 3. Plot of Maximum Power Dissipation vs. Temperature

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option	
AD 8001AN AD 8001AR AD 8001ACHIPS	-40°C to +85°C -40°C to +85°C -40°C to +85°C	8-Pin Plastic DIP 8-Pin Plastic SOIC Die Form	N -8 SO -8	
AD 8001SM D ¹ AD 8001R-EB+2 ²	-55°C to +125°C	8-Pin Cerdip SOIC Eval Board, G = +2	Q-8	

NOTES

¹Standard M ilitary D rawing D evice. Ordering N umber T BD. Contact our local sales office, representative or distributor for availability.

²Refer to Evaluation Board section.

CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD 8001 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



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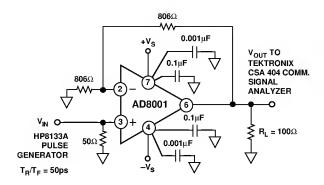


Figure 4. Test Circuit, Gain = +2

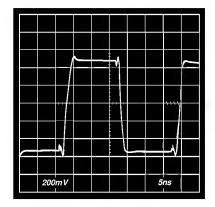


Figure 5. 1 V Step Response, G = +2

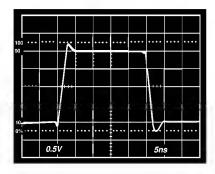


Figure 6. 2 V Step Response, G = +1

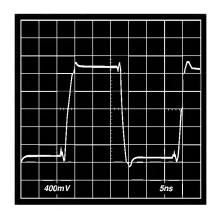


Figure 7. 2 V Step Response, G = +2

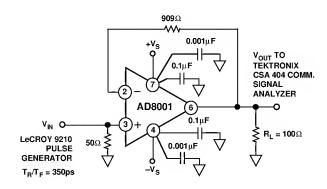


Figure 8. Test Circuit , Gain = +1

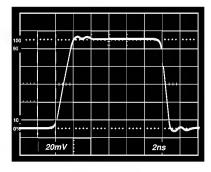


Figure 9. 100 mV Step Response, G = +1

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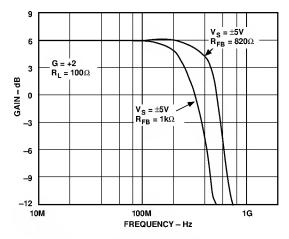


Figure 10. Frequency Response, G = +2

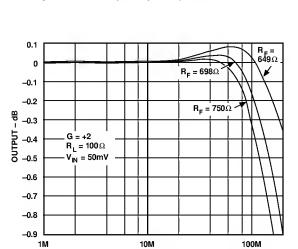


Figure 11. 0.1 dB Flatness, R Package (for N Package add 50Ω to $R_{\rm F}$)

FREQUENCY - Hz

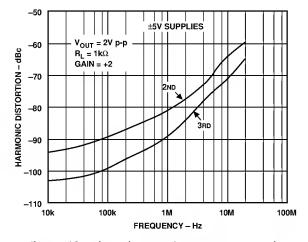


Figure 12. Distortion vs. Frequency, $R_L = 1 \text{ k}\Omega$

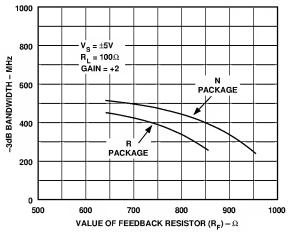


Figure 13. -3 dB Bandwidth vs. R_F

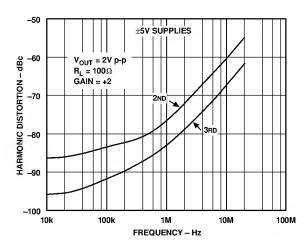


Figure 14. Distortion vs. Frequency, $R_L = 100 \,\Omega$

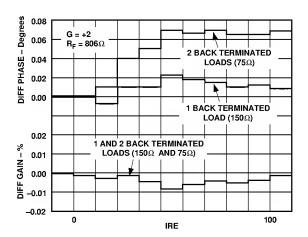


Figure 15. Differential Gain and Differential Phase

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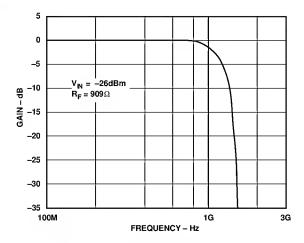


Figure 16. Frequency Response, G = +1

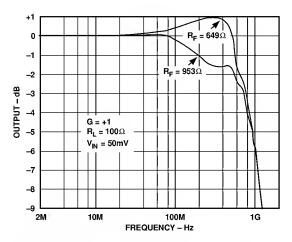


Figure 17. Flatness, R Package, G = +1 (for N Package Add 100Ω to $R_{\rm F}$)

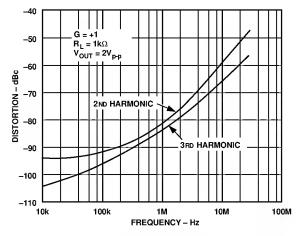


Figure 18. Distortion vs. Frequency, $R_L = 1 \text{ k}\Omega$

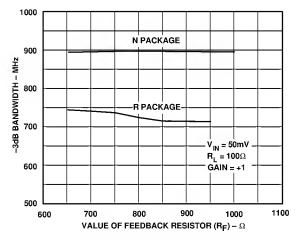


Figure 19. -3 dB Bandwidth vs. R_F , G = +1

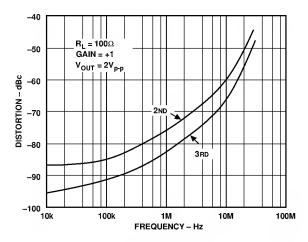


Figure 20. Distortion vs. Frequency, $R_L = 100\Omega$

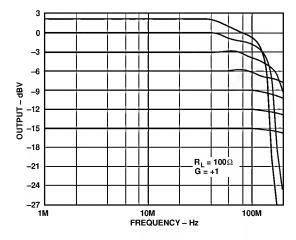


Figure 21. Large Signal Frequency Response, G = +1

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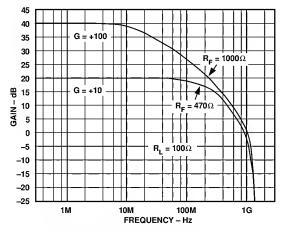


Figure 22. Frequency Response, G = +10, G = +100

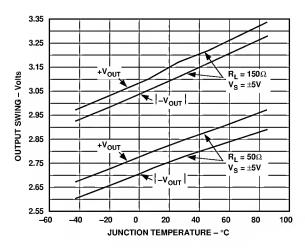


Figure 23. Output Swing vs. Temperature

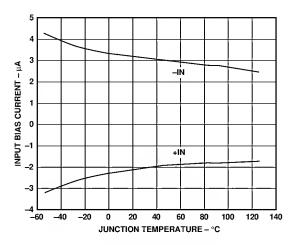


Figure 24. Input Bias Current vs. Temperature

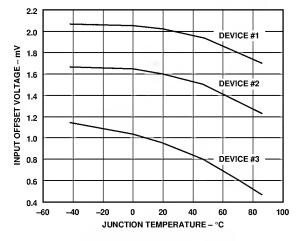


Figure 25. Input Offset vs. Temperature

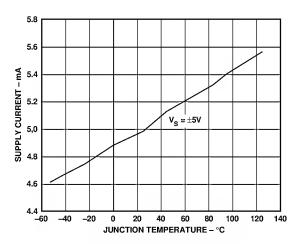


Figure 26. Supply Current vs. Temperature

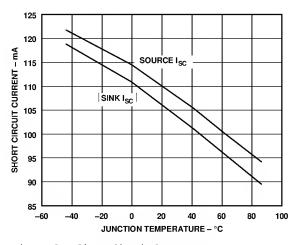


Figure 27. Short Circuit Current vs. Temperature

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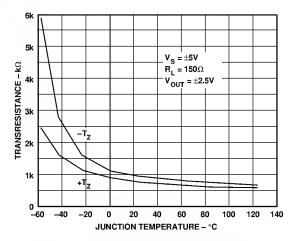


Figure 28. Transresistance vs. Temperature

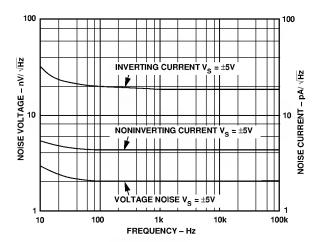


Figure 29. Noise vs. Frequency

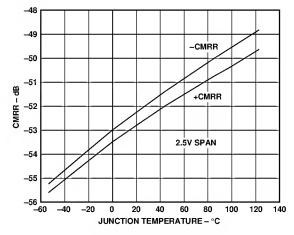


Figure 30. CMRR vs. Temperature

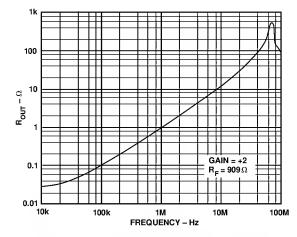


Figure 31. Output Resistance vs. Frequency

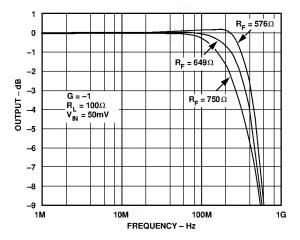


Figure 32. -3 dB Bandwidth vs. Frequency, G = -1

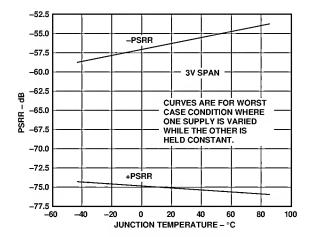


Figure 33. PSRR vs. Temperature

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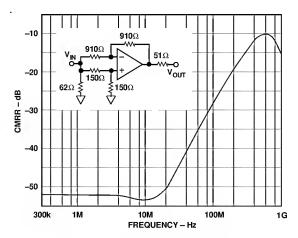


Figure 34. CMRR vs. Frequency

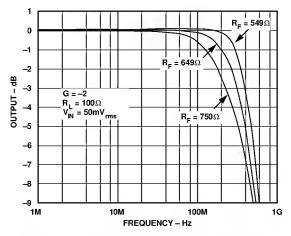


Figure 35. -3 dB Bandwidth vs. Frequency, G = -2

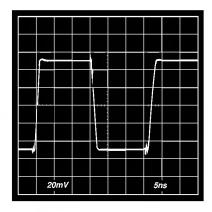


Figure 36. 100 mV Step Response, G = -1

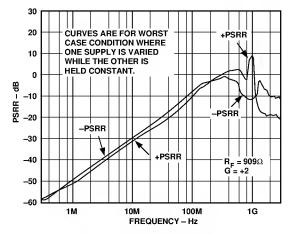


Figure 37. PSRR vs. Frequency

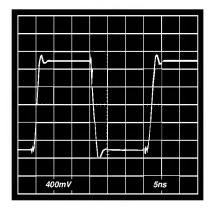


Figure 38. 2 V Step Response, G = -1

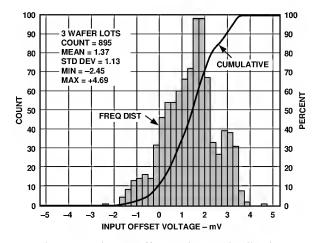


Figure 39. Input Offset Voltage Distribution

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THEORY OF OPERATION

A very simple analysis can put the operation of the AD 8001, a current feedback amplifier, in familiar terms. Being a current feedback amplifier, the AD 8001's open-loop behavior is expressed as transimpedance, $\Delta V_{\rm O}/\Delta I_{-\rm IN}$, or T $_{\rm Z}$. The open loop transimpedance behaves just as the open loop voltage gain of a voltage feedback amplifier, that is, it has a large dc value and decreases at roughly 6 dB/octave in frequency.

Since the R_{1N} is proportional to $1/g_M$, the equivalent voltage gain is just $T_Z \times g_M$, where the g_M in question is the transconductance of the input stage. This results in a low open loop input impedance at the inverting input, a now familiar result. Using this amplifier as a follower with gain, Figure 40, basic analysis yields the following result.

$$\frac{V_o}{V_{IN}} = G \times \frac{T_z(S)}{T_z(S) + G \times R_{IN} + R_1}$$

$$G = 1 + \frac{R_1}{R_2} \qquad R_{IN} = 1/g_M \approx 50 \Omega$$

Recognizing that $G \times R_{1N} << R_1$ for low gains, it can be seen to the first order that bandwidth for this amplifier is independent of gain (G). This simple analysis in conjunction with Figure 41 in fact can predict the behavior of the AD 8001 over a wide range of conditions.

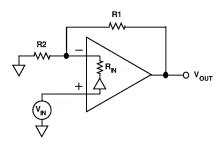


Figure 40.

C onsidering that additional poles contribute excess phase at high frequencies there is a minimum feedback resistance below which peaking or oscillation may result. This fact is used to determine the optimum feedback resistance, R $_{\rm F}$. In practice parasitic capacitance at Pin 2 will also add phase in the feedback loop, so picking an optimum value for R $_{\rm F}$ can be difficult. Figure 42 illustrates this problem. Here the fine scale (0.1 dB/div) flatness is plotted vs. feedback resistance. These plots were taken using an evaluation card which is available to customers so that these results may readily duplicated (see Evaluation Board section).

A chieving and maintaining gain flatness of better than $0.1~\mathrm{dB}$ at frequencies above $10~\mathrm{M}$ Hz requires careful consideration of several issues.

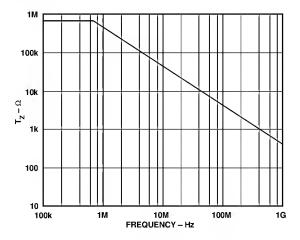


Figure 41. Transimpedance vs. Frequency

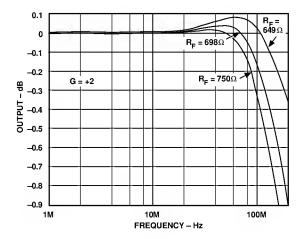


Figure 42. 0.1 dB Flatness vs. Frequency

Choice of Feedback and Gain Resistors

Because of the above mentioned relationship between the bandwidth and the feedback resistor, the fine scale gain flatness will, to some extent, vary with feedback resistance. It, therefore, is recommended that once optimum resistor values have been determined, 1% tolerance values should be used if it is desired to maintain flatness over a wide range of production lots. In addition, resistors of different construction have different associated parasitic capacitance and inductance. Surface mount resistors were used for the bulk of the characterization for this data sheet. It is not recommended that leaded components be used with the AD 8001.

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Printed Circuit Board Layout Considerations

As to be expected for a wideband amplifier, PC board parasitics can affect the overall closed loop performance. Of concern are stray capacitances at the output and the inverting input nodes. If a ground plane is to be used on the same side of the board as the signal traces, a space (5 mm min) should be left around the signal lines to minimize coupling. Additionally, signal lines connecting the feedback and gain resistors should be short enough so that their associated inductance does not cause high frequency gain errors. Line lengths on the order of less than 5 mm are recommended. If long runs of coaxial cable are being driven, dispersion and loss must be considered.

Power Supply Bypassing

Adequate power supply bypassing can be critical when optimizing the performance of a high frequency circuit. Inductance in the power supply leads can form resonant circuits that produce peaking in the amplifier's response. In addition, if large current transients must be delivered to the load, then bypass capacitors (typically greater than $1\,\mu\text{F}$) will be required to provide the best settling time and lowest distortion. A parallel combination at least 4.7 μF and between 0.1 μF and 0.01 μF is recommended. Some brands of electrolytic capacitors will require a small series damping resistor $\approx\!4.7\,\Omega$ for optimum results

DC Errors and Noise

There are three major noise and offset terms to consider in a current feedback amplifier. For offset errors refer to the equation below. For noise error the terms are root-sum-squared to give a net output error. In the circuit below (Figure 43) they are input offset (V_{10}) which appears at the output multiplied by the noise gain of the circuit $(1 + R_F/R_I)$, N oninverting input current $(I_{BN} \times R_N)$ also multiplied by the noise gain, and the inverting input current, which when divided between R_F and R_I and subsequently multiplied by the noise gain always appears at the output as $I_{BN} \times R_F$. The input voltage noise of the AD 8001 is a low 2 nV/ $\sqrt{\text{Hz}}$. At low gains though the inverting input current noise times R_F is the dominant noise source. C areful layout and device matching contribute to better offset and drift specifications for the AD 8001 compared to many other current feedback amplifiers. The typical performance curves in conjunction with the equations below can be used to predict the performance of the AD 8001 in any application.

$$V_{OUT} = V_{IO} \times \left(1 + \frac{R_F}{R_I}\right) \pm I_{BN} \times R_N \times \left(1 + \frac{R_F}{R_I}\right) \pm I_{BI} \times R_F$$

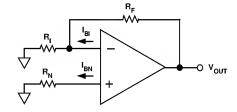


Figure 43. Output Offset Voltage

Driving Capacitive Loads

The AD 8001 was designed primarily to drive nonreactive loads. If driving loads with a capacitive component is desired, best frequency response is obtained by the addition of a small series resistance as shown in Figure 44. The accompanying graph shows the optimum value for R_{SERIES} vs. capacitive load. It is worth noting that the frequency response of the circuit when driving large capacitive loads will be dominated by the passive roll-off of R_{SERIES} and C_{L} .

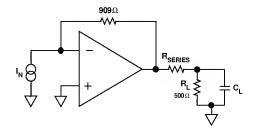


Figure 44. Driving Capacitive Loads

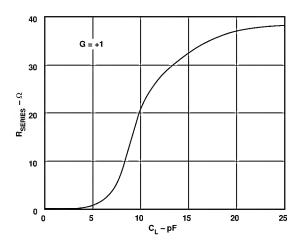


Figure 45. Recommended R_{SERIES} vs. Capacitive Load

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Communications

Distortion is a key specification in communications applications. Intermodulation distortion (IM D) is a measure of the ability of an amplifier to pass complex signals without the generation of spurious harmonics. The third order products are usually the most problematic since several of them fall near the fundamentals and do not lend themselves to filtering. Theory predicts that the third order harmonic distortion components increase in power at three times the rate of the fundamental tones. The specification of third order intercept as the virtual point where fundamental and harmonic power are equal is one standard measure of distortion performance. Op amps used in closedloop applications do not always obey this simple theory. At a gain of two the AD 8001 has performance summarized in Figure 46. Here the worst third order products are plotted vs. input power. The third order intercept of the AD 8001 is +33 dBm at 10 M H z

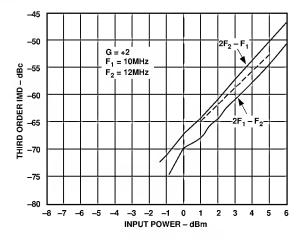


Figure 46. Third Order IMD; $F_1 = 10 \text{ MHz}$, $F_2 = 12 \text{ MHz}$

Operation as a Video Line Driver

The AD 8001 has been designed to offer outstanding performance as a video line driver. The important specifications of differential gain (0.01%) and differential phase (0.025°) meet the most exacting HDTV demands for driving one video load. The AD 8001 also drives up to two back terminated loads, as shown in Figure 47, with equally impressive performance (0.01%, 0.07°). Another important consideration is isolation between loads in a multiple load application. The AD 8001 has more than 40 dB of isolation at 5 MHz when driving two 75 Ω back terminated loads.

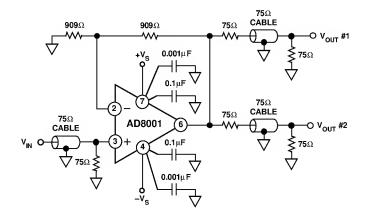


Figure 47. Video Line Driver

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Driving A-to-D Converters

The AD 8001 is well suited for driving high speed analog-to-digital converters such as the AD 9058. The AD 9058 is a dual 8-bit 50 M sps ADC. In the circuit below two AD 8001s are shown driving the inputs of the AD 9058 which are configured for 0 V to \pm 2 V ranges. Bipolar input signals are buffered, amplified (\pm 2×), and offset (by \pm 1.0 V) into the proper input range of the ADC. U sing the AD 9058's internal \pm 2 V reference connected

to both ADCs as shown in Figure 48 reduces the number of external components required to create a complete data acquisition system. The 20 Ω resistors in series with ADC input are used to help the AD8001s drive the 10 pF ADC input capacitance. The two AD8001s only add 100 mW to the power consumption while not limiting the performance of the circuit.

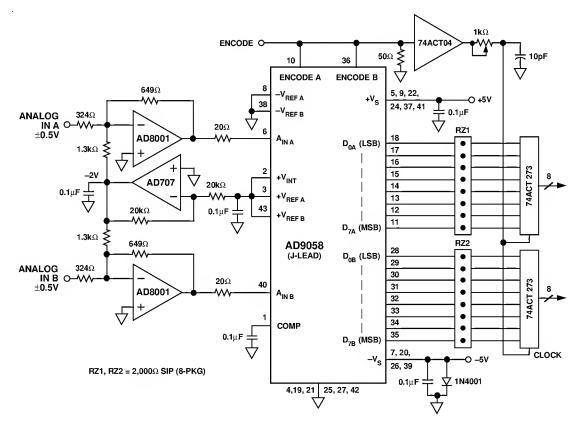


Figure 48. AD8001 Driving a Dual A-to-D Converter

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Layout Considerations

The specified high speed performance of the AD 8001 requires careful attention to board layout and component selection. Proper RF design techniques and low parasitic component selection are mandatory.

The PCB should have a ground plane covering all unused portions of the component side of the board to provide a low impedance ground path. The ground plane should be removed from the area near the input pins to reduce stray capacitance.

Chip capacitors should be used for supply bypassing (see Figure 49). One end should be connected to the ground plane and the other within 1/8 in. of each power pin. An additional large

(4.7 μ F –10 μ F) tantalum electrolytic capacitor should be connected in parallel, but not necessarily so close, to supply current for fast, large-signal changes at the output.

The feedback resistor should be located close to the inverting input pin in order to keep the stray capacitance at this node to a minimum. Capacitance variations of less than 1 pF at the inverting input will significantly affect high speed performance.

Stripline design techniques should be used for long signal traces (greater than about 1 in.). These should be designed with a characteristic impedance of 50 Ω or 75 Ω and be properly terminated at each end.

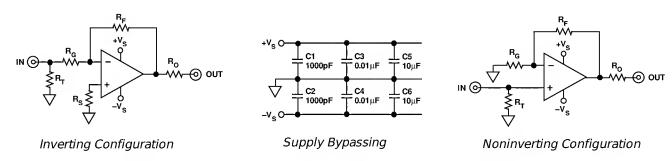


Figure 49. Inverting and Noninverting Configurations for Evaluation Boards

Table I. Recommended Component Values

	AD8001AN (DIP) Gain				AD8001AR (SOIC) Gain					
Component	-1	+1	+2	+10	+100	-1	+1	+2	+10	+100
R _F	649 Ω	1050 Ω	750 Ω	470 Ω	1000 Ω	604 Ω	953 Ω	681 Ω	470 Ω	1000 Ω
R_{G}	649 Ω	_	750 Ω	51 Ω	10 Ω	$604~\Omega$	_	$681~\Omega$	51 Ω	$10~\Omega$
R _o (Nominal)	49.9 Ω	49.9 Ω	49.9 Ω	49.9 Ω	49.9 Ω	$49.9~\Omega$	49.9 Ω	49.9Ω	49.9 Ω	$49.9~\Omega$
Rs	0 Ω	_	_	_	_	$0~\Omega$	_	_	_	_
R _T (N ominal)	54.9 Ω	49.9 Ω	49.9 Ω	49.9 Ω	49.9 Ω	$54.9~\Omega$	49.9 Ω	49.9 Ω	49.9 Ω	$49.9~\Omega$
Small Signal BW (M Hz)	340	880	460	260	20	370	710	440	260	20
0.1 dB Flatness (M H z)	105	70	105	-	-	130	100	120	-	-

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Evaluation Board

An evaluation board for the AD 8001 is available that has been carefully laid-out and tested to demonstrate that the specified high speed performance of the device can be realized. For ordering information, please refer to the Ordering Guide.

The layout of the evaluation board can be used as shown or serve as a guide for a board layout.

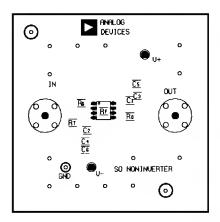


Figure 50. Evaluation Board Silkscreen (Top)

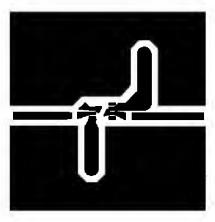


Figure 51. Evaluation Board Layout (Solder Side)

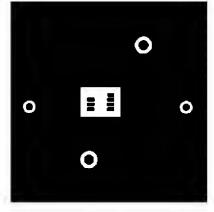


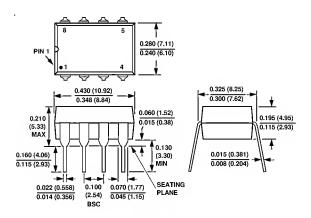
Figure 52. Evaluation Board Layout (Component Side)

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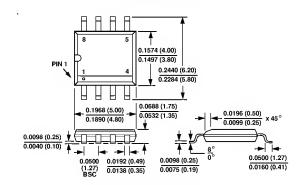
OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

8-Pin Plastic DIP (N Package)



8-Pin Plastic SOIC (SO-8 Package)



8-Pin Cerdip (Q Package)

